

**Notice of References Cited**

Application/Control No.

10/633,634

Applicant(s)/Patent Under  
Reexamination  
CHOI ET AL.

Examiner

ANTHONY BANTAMOI

Art Unit

2423

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0101282	05-2004	Kuroda et al.	386/094
*	B	US-2007/0127887	06-2007	Yap et al.	386/095
*	C	US-2003/0227485	12-2003	Krakirian et al.	345/771
*	D	US-2003/0007780	01-2003	Senoh, Takanori	386/68
*	E	US-2001/0052126	12-2001	NANKI et al.	725/55
*	F	US-5,857,059	01-1999	Yamagishi, Yoichi	386/125
*	G	US-7,434,245	10-2008	Shiga et al.	725/43
*	H	US-6,396,998	05-2002	Nozaki et al.	386/52
*	I	US-5,793,364	08-1998	Bolanos et al.	725/41
*	J	US-2004/0237108	11-2004	Drazin et al.	725/056
*	K	US-6,020,930	02-2000	Legrand, Ludovic	725/41
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.